Stephen Reynolds

List of Publications by Year in Descending Order

Source: https://exaly.com/author-pdf/3120608/stephen-reynolds-publications-by-year.pdf

Version: 2024-04-28

This document has been generated based on the publications and citations recorded by exaly.com. For the latest version of this publication list, visit the link given above.

The third column is the impact factor (IF) of the journal, and the fourth column is the number of citations of the article.

97 849 14 25 g-index

100 904 2.4 avg, IF L-index

#	Paper	IF	Citations
97	Modelling and simulation tool for off-grid PV-hydrogen energy system. <i>International Journal of Sustainable Energy</i> , 2020 , 39, 1-20	2.7	4
96	Silicon Thin Films: Functional Materials for Energy, Healthcare, and IT Applications. <i>Physica Status Solidi (A) Applications and Materials Science</i> , 2019 , 216, 1800847	1.6	1
95	Spectral matching and outdoor solar to electrical conversion efficiency in thin-film silicon multi-junction solar cells. <i>Journal of Physics: Conference Series</i> , 2017 , 794, 012025	0.3	5
94	Optical sensing of polarization using conical diffraction phenomenon. <i>Journal of Optics (United Kingdom)</i> , 2016 , 18, 025609	1.7	7
93	Micro/small wind turbine power control for electrolysis applications. <i>Renewable Energy</i> , 2016 , 87, 182-	19221	10
92	Macro Micro Studio: A Prototype Energy Autonomous Laboratory. Sustainability, 2016, 8, 500	3.6	4
91	Modelling Performance of Two- And Four-terminal Thin-film Silicon Tandem Solar Cells under Varying Spectral Conditions. <i>Energy Procedia</i> , 2015 , 84, 251-260	2.3	12
90	Equivalent-circuit and Transport-based Mobility Models of Microcrystalline Silicon Solar Cells. <i>Energy Procedia</i> , 2014 , 44, 192-202	2.3	2
89	Electronic properties of undoped microcrystalline silicon oxide films. <i>Canadian Journal of Physics</i> , 2014 , 92, 753-757	1.1	1
88	Study of electron-irradiated silicon thin films using transient photocurrent spectroscopy. <i>Journal of Physics: Conference Series</i> , 2014 , 558, 012001	0.3	
87	Transient photocurrents as a spatially resolved probe of carrier transport and defect distributions in silicon thin films. <i>Materials Science and Engineering B: Solid-State Materials for Advanced Technology</i> , 2013 , 178, 568-573	3.1	
86	Properties of thin-film silicon solar cells at very high irradiance. <i>Journal of Non-Crystalline Solids</i> , 2012 , 358, 2202-2205	3.9	2
85	Continuous wave terahertz radiation from an InAs/GaAs quantum-dot photomixer device. <i>Applied Physics Letters</i> , 2012 , 101, 081114	3.4	15
84	Modelling of two-and four-terminal thin-film silicon tandem solar cells. <i>Journal of Physics:</i> Conference Series, 2012 , 398, 012006	0.3	5
83	Equivalent-circuit Modeling of Microcrystalline Silicon pin Solar Cells prepared over a Wide Range of Absorber-layer Compositions. <i>Materials Research Society Symposia Proceedings</i> , 2010 , 1245, 1		1
82	Early exploration of MRI-compatible diagnostic ultrasound transducers 2010,		4
81	Study of thin-film silicon solar cells at irradiances above ten thousand suns. <i>Journal of Physics:</i> Conference Series, 2010 , 253, 012042	0.3	1

(2006-2010)

80	Structure-related strain and stress in thin hydrogenated microcrystalline silicon films. <i>Journal of Physics: Conference Series</i> , 2010 , 253, 012056	0.3	О
79	Carrier mobility, band tails and defects in microcrystalline silicon. <i>Journal of Physics: Conference Series</i> , 2010 , 253, 012002	0.3	5
78	Measurement and modelling of transport in amorphous semiconductors. <i>Journal of Physics: Conference Series</i> , 2010 , 253, 012001	0.3	
77	Intensity dependence of quantum efficiency and photo-gating effects in thin film silicon solar cells. <i>Physica Status Solidi C: Current Topics in Solid State Physics</i> , 2010 , 7, NA-NA		3
76	Correlation of structural and optoelectronic properties of thin film silicon prepared at the transition from microcrystalline to amorphous growth. <i>Thin Solid Films</i> , 2009 , 517, 6392-6395	2.2	12
75	Electrical properties of nanocrystalline CdSe thin films prepared by thermal vacuum evaporation. <i>Semiconductor Science and Technology</i> , 2008 , 23, 095002	1.8	25
74	Modulated photoconductivity study of nanocrystalline CdSe films. <i>Journal of Non-Crystalline Solids</i> , 2008 , 354, 2744-2747	3.9	2
73	Thermally stimulated currents in thin silicon films arising from atmospheric effects without light exposure. <i>Journal of Non-Crystalline Solids</i> , 2008 , 354, 2337-2340	3.9	2
72	Determination of the density of localized states in disordered semiconductors using transient photocurrent spectroscopy with a finite-width light pulse excitation. <i>Philosophical Magazine Letters</i> , 2008 , 88, 191-201	1	O
71	Density of states in the gap of microcrystalline silicon determined from thermally-stimulated currents. <i>Thin Solid Films</i> , 2008 , 516, 6844-6847	2.2	6
70	Thermally-Stimulated Currents in Thin-Film Semiconductors: Analysis and Modelling. <i>Materials Research Society Symposia Proceedings</i> , 2006 , 910, 2		
69	Relationship between Phase Shift, Square-Wave Response and Density of States in Modulated Photocurrent Spectroscopy. <i>Materials Research Society Symposia Proceedings</i> , 2006 , 910, 1		
68	Time-resolved Photoconductivity as a Probe of Carrier Transport in Microcrystalline Silicon. <i>Materials Research Society Symposia Proceedings</i> , 2006 , 910, 1		
67	Numerical simulation of the steady state photoconductivity in hydrogenated amorphous silicon including localized state electron hopping. <i>Journal of Physics Condensed Matter</i> , 2006 , 18, 3721-3734	1.8	9
66	Modulated photoluminescence studies for lifetime determination in amorphous-silicon passivated crystalline-silicon wafers. <i>Journal of Non-Crystalline Solids</i> , 2006 , 352, 1888-1891	3.9	32
65	Numerical modeling of thermally-stimulated currents for the density-of-states determination in thin-film semiconductors. <i>Journal of Non-Crystalline Solids</i> , 2006 , 352, 1028-1031	3.9	5
64	Metastable effects in silicon thin films: Atmospheric adsorption and light-induced degradation. Journal of Non-Crystalline Solids, 2006 , 352, 1075-1078	3.9	23
63	Electron and hole transport in microcrystalline silicon solar cells studied by time-of-flight photocurrent spectroscopy. <i>Journal of Non-Crystalline Solids</i> , 2006 , 352, 1093-1096	3.9	27

62	Atmospheric adsorption effects in hot-wire chemical-vapor-deposition microcrystalline silicon films with different electrode configurations. <i>Semiconductors</i> , 2005 , 39, 343-346	0.7	5
61	Defect states in CdSe nanocrystalline layers. <i>Physica Status Solidi (A) Applications and Materials Science</i> , 2005 , 202, 1081-1087	1.6	2
60	Transport and Meyer-Neldel Rule in Microcrystalline Silicon Films. <i>Materials Research Society Symposia Proceedings</i> , 2005 , 862, 561		4
59	Extension of the Constant Photocurrent Method to Determine Densities of Occupied and Unoccupied Localised States. <i>Materials Research Society Symposia Proceedings</i> , 2004 , 808, 591		2
58	Decay from steady-state photocurrent in amorphous semiconductors. <i>Physica Status Solidi C:</i> Current Topics in Solid State Physics, 2004 , 1, 1194-1207		9
57	Comparison of AC and DC constant photocurrent methods for determination of defect densities. Journal of Non-Crystalline Solids, 2004 , 338-340, 228-231	3.9	13
56	Aging effects in microcrystalline silicon films studied by transient photoconductivity. <i>Journal of Non-Crystalline Solids</i> , 2004 , 338-340, 421-424	3.9	20
55	Interpretation of Transient Photocurrents in Coplanar and Sandwich PIN Microcrystalline Silicon Structures. <i>Materials Research Society Symposia Proceedings</i> , 2004 , 808, 332		5
54	Depth Profiling of Light-Induced Defects in Hydrogenated Amorphous Silicon by Transient Photocurrent Spectroscopy. <i>Materials Research Society Symposia Proceedings</i> , 2003 , 762, 19131		
53	Determination of Defect Densities by Constant Photocurrent Method ©Comparison of AC and DC Methods. <i>Materials Research Society Symposia Proceedings</i> , 2003 , 762, 19121		2
52	The influence of generation and transport processes in the constant photocurrent method. <i>Journal of Materials Science: Materials in Electronics</i> , 2003 , 14, 681-684	2.1	2
51	Spatial and energetic profiling of defects in thin-film silicon. <i>Journal of Materials Science: Materials in Electronics</i> , 2003 , 14, 615-619	2.1	2
50	Analysis and modelling of generation Decombination noise in amorphous semiconductors. <i>Thin Solid Films</i> , 2003 , 427, 133-136	2.2	2
49	A Study of Electronic Defects in Hydrogenated Amorphous Silicon Prepared by the Expanding Thermal Plasma Technique. <i>Materials Research Society Symposia Proceedings</i> , 2003 , 762, 19141		1
48	Localised States in Microcrystalline Silicon Photovoltaic Structures Studied by Post-Transit Time-of-Flight Spectroscopy. <i>Materials Research Society Symposia Proceedings</i> , 2003 , 762, 431		2
47	Transient Photoconductivity for the Identification of Spatial Inhomogeneities in the Defect Density in Amorphous Silicon. <i>Physica Status Solidi A</i> , 2002 , 191, 530-534		1
46	Depth profiling in amorphous and microcrystalline silicon by transient photoconductivity techniques. <i>Journal of Physics Condensed Matter</i> , 2002 , 14, 6909-6915	1.8	5
45	Size-Dependent Absorption and Defect States in CdSe Nanocrystals in Various Multilayer Structures. <i>Journal of Nanoscience and Nanotechnology</i> , 2002 , 2, 645-652	1.3	5

(2000-2002)

44	Probing localized states distributions in semiconductors by Laplace transform transient photocurrent spectroscopy. <i>Journal of Non-Crystalline Solids</i> , 2002 , 299-302, 541-545	3.9	4	
43	The influence of defects on response speed of high gain two-beam photogating in a-Si:H PIN structures. <i>Journal of Non-Crystalline Solids</i> , 2002 , 299-302, 594-598	3.9	1	
42	Transient Photocurrents in Microcrystalline Silicon Films. <i>Materials Research Society Symposia Proceedings</i> , 2002 , 715, 2121		8	
41	Size-dependent absorption and defect states in CdSe nanocrystals in various multilayer structures. Journal of Nanoscience and Nanotechnology, 2002 , 2, 645-52	1.3		
40	Depth profiling and the effect of oxygen and carbon on the photoelectrical properties of amorphous silicon films deposited using tungsten wire filaments. <i>Thin Solid Films</i> , 2001 , 395, 130-133	2.2	7	
39	Density-of-states distribution in AlGaN obtained from transient photocurrent analysis. <i>Materials Science and Engineering B: Solid-State Materials for Advanced Technology</i> , 2001 , 82, 206-208	3.1	5	
38	Defect pool model based transient photoconductivity and the conduction band tail profile in a-Si:H. <i>Journal of Physics Condensed Matter</i> , 2001 , 13, 10969-10977	1.8	3	
37	Laplace-transform Transient Photocurrent Spectroscopy as a Probe of Metastable Defect Distributions in Hydrogenated Amorphous Silicon. <i>Materials Research Society Symposia Proceedings</i> , 2001 , 664, 1931		4	
36	Effect of Experimental Noise on Recovery of the Electronic Density of States from Transient Photocurrent Data. <i>Materials Research Society Symposia Proceedings</i> , 2001 , 664, 2261			
35	Generation- Recombination Noise in Amorphous Semiconductors. <i>Materials Research Society Symposia Proceedings</i> , 2001 , 664, 2371		1	
34	Improved High Resolution Post-Transit Spectroscopy for Determining the Density of States in Amorphous Semiconductors. <i>Materials Research Society Symposia Proceedings</i> , 2000 , 609, 2761			
33	A Laplace Transform Technique for Direct Determination of Density of Electronic States in Disordered Semiconductors from Transient Photocurrent Data. <i>Materials Research Society Symposia Proceedings</i> , 2000 , 609, 2781		3	
32	High resolution density of states spectroscopy in semiconductors by exact post-transit current analysis. <i>Journal of Applied Physics</i> , 2000 , 88, 1190-1192	2.5	5	
31	An experimental evaluation of transient and modulated photocurrent density-of-states spectroscopies. <i>The Philosophical Magazine: Physics of Condensed Matter B, Statistical Mechanics, Electronic, Optical and Magnetic Properties</i> , 2000 , 80, 547-559		34	
30	Interpreting transient photocurrents as a signature of the density of states distribution: the profound importance of the short-time decay. <i>Journal of Non-Crystalline Solids</i> , 2000 , 266-269, 362-366	3.9	5	
29	A comparative study of photoconductivity and carrier transport in oligomeric films. <i>Journal of Non-Crystalline Solids</i> , 2000 , 266-269, 994-998	3.9	8	
28	An enhanced resolution technique for determination of the distribution of localized states in semiconductors from transient photocurrents. <i>Applied Physics Letters</i> , 2000 , 76, 3085-3087	3.4	3	
27	Bandwidth considerations in modulated and transient photoconductivity measurements to determine localized state distributions. <i>Journal of Applied Physics</i> , 2000 , 88, 278-282	2.5	4	

26	Transient photoconductivity, density of tail states and doping effect in amorphous silicon. <i>Solid State Communications</i> , 1999 , 112, 535-539	1.6	8
25	Investigation of collection efficiencies much larger than unity in a-Si:H p-i-n structures. <i>Journal of Applied Physics</i> , 1999 , 85, 296-301	2.5	8
24	Photoconductivity Transient Response from the Steady State in Amorphous Semiconductors. Materials Research Society Symposia Proceedings, 1999 , 557, 421		2
23	Collection Efficiencies Greater Than Unity by Electron Or Hole Gating in a-Si:H p-i-n Diodes. Materials Research Society Symposia Proceedings, 1999 , 557, 475		1
22	An Experimental Evaluation of Modulated Photocurrent Spectroscopy as A Density of States Probe. <i>Materials Research Society Symposia Proceedings</i> , 1999 , 557, 427		3
21	Sign reversal in transient photoconductivity in the presence of optical bias in undoped homogeneous a-Si:H. <i>Journal of Non-Crystalline Solids</i> , 1998 , 227-230, 211-215	3.9	3
20	Noise and modulated photocurrents in amorphous semiconductors. <i>Journal of Non-Crystalline Solids</i> , 1998 , 227-230, 233-237	3.9	7
19	Effects of bandwidth limitations on the localized state distribution calculated from transient photoconductivity data. <i>Journal of Applied Physics</i> , 1998 , 83, 4782-4787	2.5	5
18	Evaluation of the DICE analysis method for a-Si:H p-i-n devices. <i>Journal of Non-Crystalline Solids</i> , 1996 , 198-200, 1221-1225	3.9	4
17	Measurement and modelling of vibrational mode lineshape and linewidth in inelastic electron tunnelling spectroscopy. <i>Surface Science</i> , 1996 , 368, 324-329	1.8	6
16	The Study of Space Charge Effects by Spectral Response, Steady State Charge Collection and Transient Photocurrents in Thick a-Si:H Pin-Diodes. <i>Materials Research Society Symposia Proceedings</i> , 1996 , 420, 251		3
15	Electroporation protocols for Agrobacterium. <i>Methods in Molecular Biology</i> , 1995 , 44, 405-12	1.4	25
14	A high-voltage, high-frequency linear amplifier/driver for capacitive loads. <i>Measurement Science and Technology</i> , 1992 , 3, 283-288	2	3
13	Determination of gap-state distributions in amorphous semiconductors from transient photocurrents using a fourier transform technique. <i>Solid State Communications</i> , 1992 , 83, 401-405	1.6	65
12	Modulated and transient photoconductivity in a-As2 Se3. <i>Journal of Non-Crystalline Solids</i> , 1991 , 137-138, 951-954	3.9	24
11	An evaluation of phase-shift analysis of modulated photocurrents. <i>The Philosophical Magazine: Physics of Condensed Matter B, Statistical Mechanics, Electronic, Optical and Magnetic Properties</i> , 1990 , 62, 29-45		138
10	A phenomenological model of switching in metal-thin insulator-semiconductor-semiconductor devices: A development of the analogy with the thyristor. <i>Journal of Applied Physics</i> , 1989 , 65, 2102-2110	₫·5	1
9	Anomalous high zero bias resistance in metal - amorphous silicon - metal structures. <i>Journal of Non-Crystalline Solids</i> , 1989 , 115, 171-173	3.9	11

LIST OF PUBLICATIONS

8	Bias polarity-dependent changes in vibrational mode energy in inelastic electron tunnelling spectroscopy. <i>Journal of Physics C: Solid State Physics</i> , 1987 , 20, 4297-4306		4	
7	Amorphous semiconductors. <i>Physics in Technology</i> , 1987 , 18, 193-203		2	
6	Pre-formed J-V and C-V characteristics of a-Si:H p+ ni junctions. <i>Journal of Non-Crystalline Solids</i> , 1987 , 97-98, 1331-1334	3.9		
5	Transient current instabilities in a-Si: Hp+ni structures. <i>IEE Proceedings I: Solid State and Electron Devices</i> , 1987 , 134, 1		1	
4	The application of inelastic electron tunnelling spectroscopy to adhesive bonding. <i>International Journal of Adhesion and Adhesives</i> , 1985 , 5, 59-65	3.4	11	
3	The switching mechanism in amorphous silicon junctions. <i>Journal of Non-Crystalline Solids</i> , 1985 , 77-78, 1373-1382	3.9	59	
2	Inelastic electron tunnelling spectroscopy of silane coupling agents. <i>Surface and Interface Analysis</i> , 1984 , 6, 40-45	1.5	33	
1	An adhesive study by electron tunnelling: Ethyl Eyanoacrylate adsorbed on an oxidized aluminium surface. <i>Spectrochimica Acta Part A: Molecular Spectroscopy</i> , 1982 , 38, 103-111		19	